# -48 V Hot Swap Controller for Redundant Supply Systems

The TPS2398 and TPS2399 integrated circuits are hot swap power managers optimized for use in nominal -48 V systems. They incorporate an improved circuit breaker response that provides rapid protection from short circuits, while still enabling plug-ins to tolerate large transients that can be generated by the sudden switchover to a higher voltage supply. They are designed for supply voltage ranges up to -80 V, and are rated to withstand spikes to -100 V. In conjunction with an external N-channel FET and sense resistor, they can be used to enable live insertion of plug-in cards and modules in power systems. Both devices provide load current slew rate and eak magnitude limiting, easily programmed by sense resistor valuand and single external capacitor.

#### **Features**

- Wide Input Supply: -36 V to -80 V
- Transient Rating to -100 V
- Improved Transient Response
- Enable Input (EN)
- Programmable Current Limit
- Programmable Current Slew R
- Fault Timer to Eliminate Name 1 rips
- Open-Drain Power Gr 1 Ot F
- MSOP-8 Package
- These are Pb-F vice

#### Typical Applic ions

- -48 V Distrit and Pow Systems
- Redundant Negal. voltage Supplies
- Central Office Switching Systems

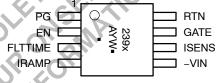


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# PIN CONNECTIONS AND MARKING DIAGRAM



(Top View)

239x = Specific Device Code

x = 8 or 9

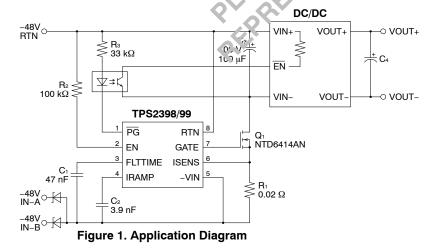
A = Assembly Location

Y = Year W = Work Week ■ = Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 15 of this data sheet.



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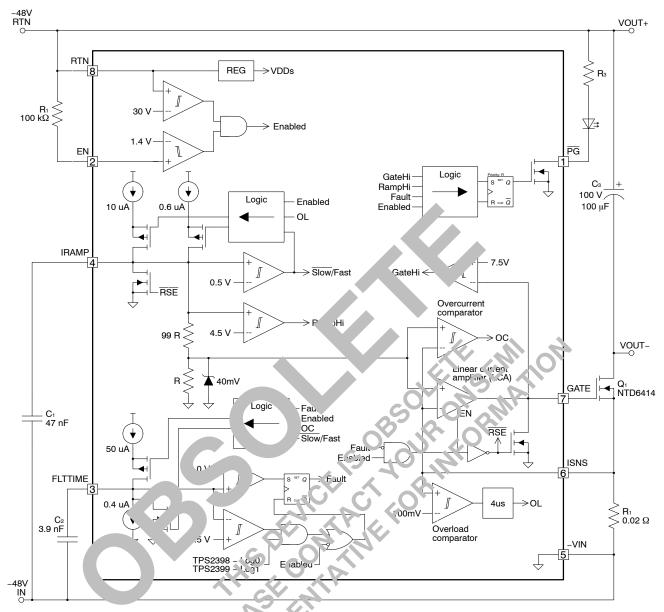


Figure 2 Marnal Block Diagram

Table 1. PIN FUNCTION DESCRIPT ON

Pin Number	Pin Name	Description			
2	EN	E. ح.J.e input to turn on/off power to the load			
1	PG	Open-drain, active-low indication of a load power good condition.			
3	FLTTIME	Connection for user-programming of the fault timeout period.			
7	GATE	Gate drive for external N-channel FET			
4	IRAMP	Programming input for setting the inrush current slew rate.			
6	ISENS	Current sense input.			
8	RTN	Positive supply input for the TPS2398 and TPS2399.			
5	-VIN	Negative supply input and reference pin for the TPS2398 and TPS2399.			

#### **Table 2. ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Input voltage range, all pins except RTN, EN, PG (Note 1)		-0.3 to 15	V
Input voltage range, RTN (Note 1)	RTN	-0.3 to 100	V
Input voltage range, EN (Notes 1, 2)	EN	-0.3 to 100	V
Output voltage range, PG (Notes 1, 3)	PG	-0.3 to 100	V
Continuous output current, PG	I <sub>PG</sub>	10	mA
Continuous total power dissipation, T <sub>A</sub> < 25	P <sub>D(MAX)</sub>	420	mW
Operating junction temperature range	$T_{J(MAX)}$	-40 to 125	°C
Storage temperature range	T <sub>STG</sub>	-55 to 150	°C
Lead temperature soldering 1.6 mm (1/16 inch) from case for 10 seconds	JOL	260	°C
Human Body Model (HBM) (Note 4)	D 1	2.0	kV
Charged Device Model (CDM) (Note 4)	ESL	1.5	kV

Stresses exceeding those listed in the Maximum Ratings table may damage 'de If any or nese limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Refer to ELECTRICAL CHARACTERISTICS and APPLICATION IN PRIMATION to afe Operating Area.
- 2. With 100-k $\Omega$  minimum input series resistance, -0.3 V to 15 V with low in explanation and input series resistance, -0.3 V to 15 V with low in explanation.
- 3. With 10-k $\Omega$  minimum input series resistance, -0.3 V to 80 V with v pedan e.
- 4. All pins except RTN pin which is specified up to 1.0 kV.

## Table 3. RECOMMENDED OPERATING CONDIT. 15

	Rating		Nom	Max	Unit
Nominal input supply, –VIN to RTN		S	-80	-36	V
Operating ambient temperature		(A)	10	85	°C

Functional operation above the stresses .....in the \_\_\_\_ended Operating \( \text{Tangen} \) of im, \( \text{Ted.} \) Extended exposure to stresses beyond the Recommended Operating Ranges \_\_nits \( \text{m} \) \( \text{qect device reliability} \)

#### Table 4. DISSIPATION RATES TABLE

Package	1A < 25°C Derating Factor	T <sub>A</sub> < 85°C
MSOP-8	420 mW 4.3 mW/°C	160 mW

## Table 5. ELEC RICAL JAN. STERISTICS

 $V_{I(-VIN)} = -48 \text{ V}$  th respec RTN,  $V_{I(EN)} = 2.0 \text{ V}$   $V_{I(ISEN)} = 0 \text{ V}$ . Unoutputs unloaded, device not in fault mode,  $V_{IJ} = 2.0 \text{ V}$  violess otherwise noted. The substitution of the

otherwise noted. 9 Min ar Max specif	ication, are givaranteed $t - t0^{\circ}C \le T_{J} \le 85^{\circ}C$ . (Note	;s o, o <sub>)</sub>		T				
Para.	Te. Conditions	Symbol	Min	Тур	Max	Unit		
INPUT SUPPLY								
Supply current, RTN	TV.(r,(N) = 4c.)	I <sub>CC</sub>		310	450	μΑ		
	$V_{I(R),V} = 30 \text{ V}$			310	450	μΑ		
UVLO threshold, input voltage rising	つ うれE pull-up, referenced to RTN	V <sub>UVLO_L</sub>	-36	-30	-25	V		
UVLO hysteresis	V.	$V_{HYS}$	1.8	2.3	3.0	V		
ENABLE INPUT (EN)								
Threshold voltage, input voltage rising	To GATE pull-up	$V_{TH}$	1.25	1.35	1.5	V		
EN hysteresis		V <sub>HYS_EN</sub>	20	40	90	mV		
High-level input current	V <sub>I(EN)</sub> = 5 V	I <sub>IH</sub>	-2	1	2	μΑ		
LINEAR CURRENT AMPLIFIER (LCA)								
High-level output, GATE	V <sub>I(ISENS)</sub> = 0 V	V <sub>OH</sub>	11	14	17	V		
Output sink current	V <sub>I(ISENS)</sub> = 80 mV, V <sub>O(GATE)</sub> = 5 V, Fault mode	I <sub>SINK</sub>	50	100		mA		
Input current, ISENS	0 V < V <sub>I(ISENS)</sub> < 0.2 V	I <sub>I</sub>	-1		1	μΑ		

- 5. All voltages are with respect to the -VIN terminal unless otherwise stated.
- 6. Currents are positive into and negative out of the specified terminal.

## **Table 5. ELECTRICAL CHARACTERISTICS**

 $V_{I(-VIN)} = -48 \text{ V with respect to RTN, } V_{I(EN)} = 2.8 \text{ V, } V_{I(ISENS)} = 0 \text{ V, all outputs unloaded, device not in fault mode, } T_J = 25^{\circ}C; \text{ unless otherwise noted.}$  The Min and Max specifications are guaranteed at  $-40^{\circ}C \leq T_J \leq 85^{\circ}C$ . (Notes 5, 6)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit		
LINEAR CURRENT AMPLIFIER (LCA)								
Reference clamp voltage	V <sub>O(IRAMP)</sub> = open	V <sub>REF_K</sub>	33	40	46	mV		
Input offset voltage	V <sub>O(IRAMP)</sub> = 2 V	V <sub>IO</sub>	-7		6	mV		
RAMP GENERATOR								
IRAMP source current, slow turn-on rate	$V_{O(IRAMP)} = 0.25 \text{ V}$	I <sub>SRC1</sub>	-850	-600	-400	nA		
IRAMP source current, normal rate	V <sub>O(IRAMP)</sub> = 1 V, 3 V	I <sub>SRC2</sub>	-11	-10	-9	μΑ		
Low-level output voltage	V <sub>I(EN)</sub> = 0 V	V <sub>OL</sub>			5	mV		
Voltage gain, relative to ISENS	V <sub>O(IRAMP)</sub> = 1 V, 3 V	$A_V$	9.5	10	10.5	mV/V		
OVERLOAD COMPARATOR	OVERLOAD COMPARATOR							
Current overload threshold, ISENS		/H_OL	80	100	120	mV		
Glitch filter delay time	V <sub>I(ISENS)</sub> = 200 mV	t <sub>DLY</sub>	2	4	7	μs		
FAULT TIMER								
Low-level output voltage	V <sub>I(EN)</sub> = 0 V	V <sub>OL</sub>			5	mV		
Charging current, current limit mode	$V_{I(ISENS)} = 80 \text{ mV}, V_{O(FL)} = 7$	I <sub>CHG</sub>	-55	-20	-45	μΑ		
Fault threshold voltage		V <sub>FL</sub> -	3.75	4.0	4.25	V		
Discharge current, retry mode (TPS2399)	$V_{I(ISENS)} = 80 \text{ n.}$ $V_{O(FLT)} = 2 \text{ V, Fault Moq}$	الحور		0.38	0.75	μΑ		
Output duty cycle (TPS2399)	co	10 1		0.8	1.5	%		
Discharge current, timer reset mode	V <sub>O</sub> <sub>TTIME)</sub> = 2	I <sub>EC7</sub>		1		mA		
PG OUTPUT								
High-level output (leakage) current	$V' = 0 \text{ V, V}_{O(PG)} = 65 \text{ V}$	I <sub>OH</sub>			10	μΑ		
Driver ON resistance	I <sub>O(PC</sub> 1 mA	R <sub>DS(ON)</sub>		35	80	Ω		

<sup>5.</sup> All voltages are with resr in to a -VII in all unless of the wise stated

s indirected in the Electrical Characteristics וייני the listed test conditions, unless otherwise noted. Product e Electrical Characteristics ייני the listed test conditions, unless otherwise noted. Product e Electrical Characteristics ייני under different conditions. Product parametric performan performance may r cate

<sup>6.</sup> Currents are positive i and out of the specificd 'erminal.

## **TYPICAL CHARACTERISTICS**

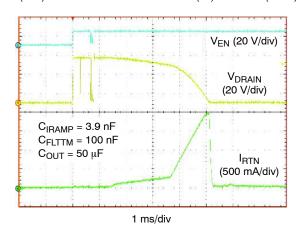


Figure 3. Live Insertion Event,  $V_{IN} = -48 \text{ V}$ 

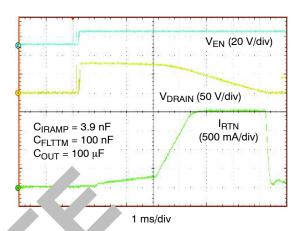
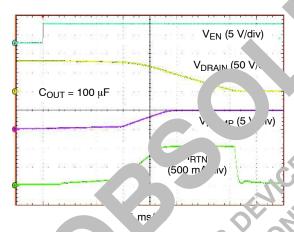


Figure - ... ve Insertion Event, V<sub>IN</sub> = -80 V



Figur 5. Star up trom Enable, V.:. -80 V

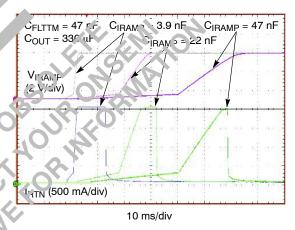


Figure 6. Output Current Ramp Profiles

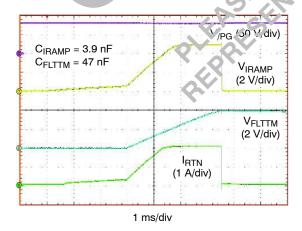


Figure 7. Turn-On into Short (TPS2399 only)

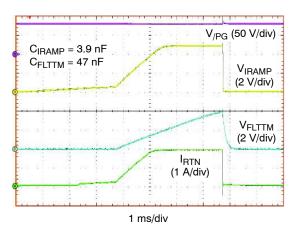


Figure 8. Turn-On into Short (TPS2398 only)

#### **TYPICAL CHARACTERISTICS**

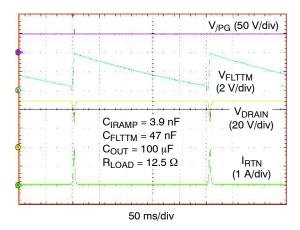


Figure 9. Fault-Retry Operation (TPS2399 only)

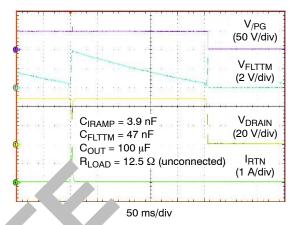


Fig. 10. Recovery from a Fault (TPS2399 only)

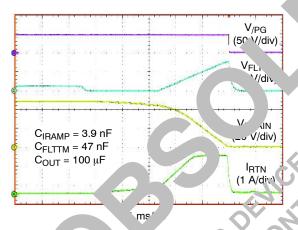


Figure 1. Rec Pry . om a Fault - E pande 1
Vie (TPS2399 only)

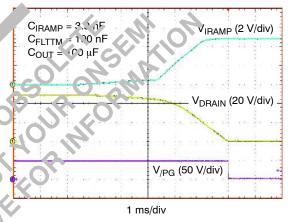


Figure 12. PG Ouput Timing – Voltage Qualified

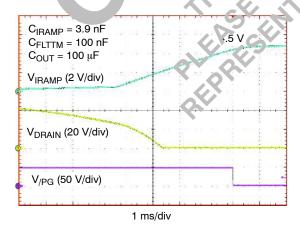


Figure 13. PG Ouput Timing – Current Qualified

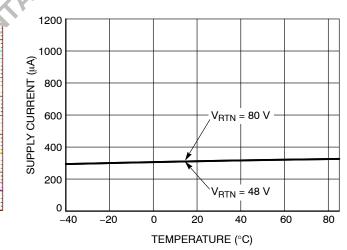


Figure 14. Supply Current

## **TYPICAL CHARACTERISTICS**

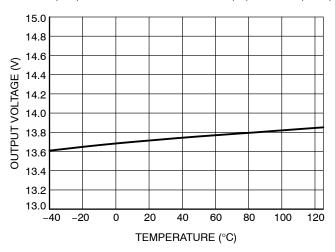


Figure 15. GATE High Output Voltage

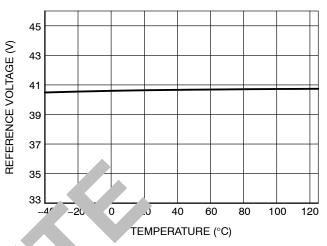


Figure 16. Reference Clamp Voltage

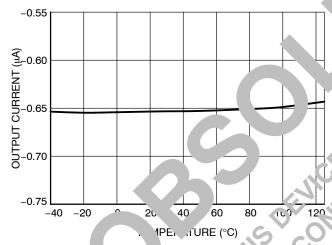


Figure 7. IRAM Output Current. Slow hate

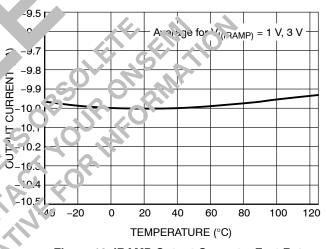


Figure 18. IRAMP Output Current – Fast Rate

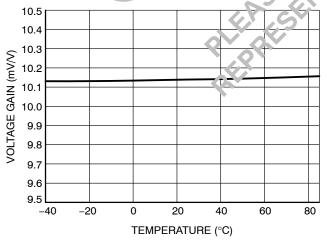


Figure 19. Voltage Gain, relative to ISNS

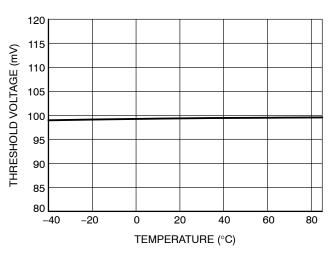


Figure 20. Current Overload Threshold, ISNS

## **TYPICAL CHARACTERISTICS**

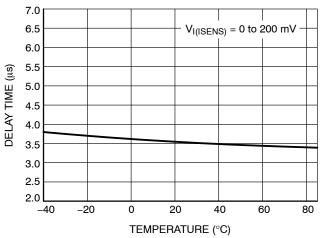
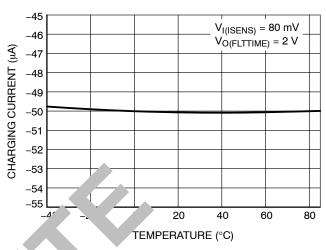
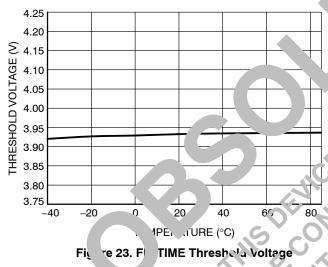


Figure 21. Glitch Filter Delay Time



igure 22. FLTTIME Charging Current



Fi re 23. F

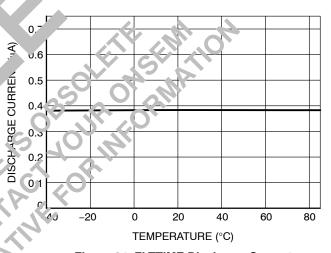


Figure 24. FLTTIME Discharge Current

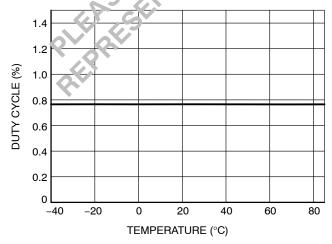


Figure 25. Fault-Retry Duty Cycle

#### **DETAILED PIN DESCRIPTIONS**

#### ΕN

Enable input to turn on/off power to the load. The EN pin is referenced to the -VIN potential of the circuit. When this input is pulled high (above the nominal 1.4 V threshold) the device enables the GATE output, and begins the ramp of current to the load. When this input is low, the linear current amplifier (LCA) is disabled, and a large pull-down device is applied to the FET gate, disabling power to the load.

#### **FLTTIME**

Connection for user-programming of the fault timeout period. An external capacitor connected from FLTTIME to -VIN establishes the timeout period to declare a fault condition. This timeout protects against indefinite current sourcing into a faulted load, and also provides a filter against nuisance trips from momentary current spikes or surges. The TPS2398 and TPS2399 define a fault condition as voltage at the ISENS pin at or greater than the 40 mV fault threshold. When a fault condition exists, the timer is active. The devices manage fault timing by charging the external capacitor to the 4 V fault threshold, then subsequently discharging it to reset the timer (TPS2398), or disch it at approximately 1% the charge rate to establish the cycle for retrying the load (TPS2399). internal fault latch is set (timer expired), pass F rapidly turned off, and the /PG output is deserted.

#### **GATE**

Gate drive for external N-chan. ∠Γ. \ len enabled, and the input supply is abor ... UVLC +h \_nold, the gat ? drive is enabled and the vice charging an external capacitor connected to the MP in This pin voltage is rence of ge at the non-inverting used to develop t1 input of the integral LCA. The averting input is connected ENS. The LCA and to slew the to the current so e node, pass FET gate is force to ISENS voltage to track the reference. The reference is internally clamped at 10 mV so the maximum current that can be sourced to the lead is determined by the sense resistor v2'/02  $I_{MAX} \le 40 \text{ mV} / R_{SNS}$ . Once the load v. (tage  $h_a$  ramped up to the input dc potential, and current demand drops off, the LCA drives the GATE output to about 1.7 to fully enhance the pass FET, completing the low-impedance supply return path for the load.

#### **IRAMP**

Programming input for setting the inrush current slew rate. An external capacitor connected between this pin and -VIN establishes the load current slew rate whenever power

to the load is enabled. The device charges the external capacitor to establish the reference input to the LCA. The closed–loop control of the LCA and pass FET acts to maintain the current sense voltage at ISENS at the reference potential. Since the sense voltage is developed as the drop across a resistor, the charging current ramp rate is set by the voltage ramp rate at the IRAMP pin. When the output is disabled via the EN input or due to a load fault, the capacitor is discharged and held low to initialize for the next turn–on.

#### **ISENS**

Current send input. An external low value resistor connected between this pin and -VIN is used to feedback current mage trainformation to the TPS2398/99. There are trainformation to the ISE pin. During charging of the load's input capacitate or during other periods of excessive demand, the HSPM at to limit this voltage to 40 mV. Whenever the ISE pin is charged to activate the timer. If, when the solution is capply to activate the timer. If, when the solution to the SENS voltage to exceed 100 mV (the overload threshold), the GATE pin is pulled low rapidly, bypassing the fault timer.

#### PG

Cren-drain active now indication of load power good. A prower good statulist declared when the output is enabled, the GATE pin voltage has ramped to at least 7.5 V, and the voltage or the IRAMP pin exceeds approximately 4.5 V. This last condition assures that full programmed sourcing current is available prior to declaring power good, even with very slow current ramp rates. This additional protection prevents potential discharging of the module input bulk capacitance during load turn-on.

#### RTN

Positive supply input for the TPS2398/99. For negative voltage systems, the supply pin connects directly to the return node of the input power bus. Internal regulators lower down the input voltage to generate the various supply levels used by the TPS2398 and TPS2399.

#### -VIN

Negative supply input and reference pin for the TPS2398/99. This pin connects directly to the input supply negative rail. The input and output pins and all internal circuitry are referenced to this pin, so it is essentially the GND or VSS pin of the device.

#### **APPLICATIONS INFORMATION**

#### General

When a plug-in module or printed circuit card is inserted into a live chassis slot, discharged supply bulk capacitance on the board can draw huge transient currents from the system supplies. Without some form of inrush limiting, these currents can reach peak magnitudes ranging up to several hundred amps, particularly in high-voltage systems. Such large transients can damage connector pins, PCB etch, and plug-in and supply components. In addition, current spikes can cause voltage droops on the power distribution bus, causing other boards in the system to reset.

The TPS2398 and TPS2399 are hot swap power managers designed to limit these peaks to preset levels, as well as control the slew rate (di/dt) at which charging current ramps to the user-programmed limit. These devices use an external N-channel pass FET and sense element to provide closed-loop control of current sourced to the load. Input supply under-voltage lockout (UVLO) protection allows hot swap circuits to turn on automatically with the application of power, or to be controlled with a system command via the EN input. External capacitors control both the current ramp rate, and the time-out period for ad voltage ramping. In addition, an interr erlc. comparator provides circuit breaker pro ction. insi shorts occurring during steady-state ost-turi operation of the card.

The TPS2398 and TPS2399 o rate directly from the input supply (nominal -48 VL - - - VIN pin connects to the negative v - e rail, and ne RTN pin connects to the supply r - rn. - rail regulators convert input power to the supply of the end of the supply of the end of the end of the supply of the end of th

Once enabled, and when the input supply is above the UVLO threshold, the GATE pull-down is removed, the linear control amplifier (LCA) is evibled, and a large discharge device in the RAMP CONTROL STOCK is turned off. Subsequently, a small current source is now able to charge an external capacitor connected to the IRAMP pin. This results in a linear voltage ramp at IRAMP. The voltage ramp on the capacitor actually has two discrete slopes. As shown in Figure 2, charging current is supplied from either of two sources. Initially at turn-on, the 600 nA source is selected, to provide a slow turn-on rate. This slow turn-on helps ensure that the LCA is pulled out of saturation, and is slewing to the voltage at its non-inverting input before normal rate load charging is allowed. This mechanism helps reduce current steps at turn-on. Once the voltage at the IRAMP pin reaches approximately 0.5 V, an internal comparator de-asserts the SLOW signal, and the 10 µA source is selected for the remainder of the ramp period.

The voltage at IRAMP is divided down by a factor of 100, and applied to the non-inverting input of the LCA. Load current magnitude information at the ISENS pin is applied to the inverting input. This voltage is developed by connecting the current sense resistor between ISENS and −VIN. The LCA controls the gate of the external pass FET to force the ISENS voltage to track the divided down IRAMP voltage. Consequently, the load current slew rate tracks the linear voltage ramp at the IRAMP pin, producing a linear di/dt of the load current. The IRAMP capacitor is charged to about 5 V; however, the LCA input is clamped at 40 mV. There 1.e, the current sourced to the load during turn-on is 1. ated 1. a value given by I<sub>MAX</sub> ≤ 40 mV / R<sub>SNS</sub>, where P NS 2. valv 3 fthe sense resistor.

The esultan. 2 current, regulated by the controller, charge. The mode e's input bulk capacitance in a safe ashion. The normal conditions, this capacitance eventually charges up to the dc input potential. At this point, a load demand drops off, and the voltage at ISENS decreases. The LCA now drives the CATE output to its safe rail.

The device a rects this condition as the GATE voltage rises through 7.5 V, taches this status and asserts the /PG output. In the full sounced contain limit is not yet available to the love, as evice need by the IRAMP voltage being less than 5 V then the /PG assertion is delayed until that condition is also met.

The peak, steady-state GATE pin output, typically 14 V, ensures sufficient overdrive to fully enhance the external F5<sup>n</sup>, which not exceeding the typical 20 V V<sub>GS</sub> rating of common N-channel power FETs.

Tack timing is accomplished by connecting a capacitor between the FLTTIME and -VIN pins, allowing user-programming of the timeout period. Whenever the hot swap controller is in current control mode as described above, the LCA asserts an overcurrent indication - OC signal in the Figure 2. Overcurrent fault timing is inhibited during the slow turn-on portion of the IRAMP waveform. However, once the device transitions to the normal rate current ramp ( $V_{IRAMP} \ge 0.5 \text{ V}$ ), the external capacitor is charged by a 50 µA source, generating a voltage ramp at the FLTTIME pin. If the load voltage ramps successfully, the fault capacitor is discharged, and load initialization can begin. However, if the timing capacitor voltage attains the 4 V fault threshold, the LCA is disabled, the pass FET is rapidly turned off, and the fault is latched. Fault capacitor charging ceases, and the capacitor is then discharged. In addition, latching of a fault condition causes rapid discharge of the IRAMP capacitor. In this manner, the soft-start function is then reset and ready for the next output enable, if and when conditions permit.

Subsequent to a plug-in's start-up, and during the module's steady-state operation, load faults that force current limit operation also initiate fault timing cycles as

described above. In this case, a fault timeout also clears the previously latched power good status.

The TPS2398 latches off in response to faults; once a fault timeout occurs, a large NMOS device is activated to rapidly discharge the external capacitor, resetting the timer for any subsequent device reset. The TPS2398 can only be reset by cycling power to the device, or by cycling the EN input.

In response to a latched fault condition, the TPS2399 enters a fault retry mode, wherein it periodically retries the load to test for continued existence of the fault. In this mode, the FLTTIME capacitor is discharged slowly by a about a 0.4 µA constant–current sink. When the voltage at the FLTTIME pin decays below 0.5 V, the LCA and RAMP CONTROL circuits are re–enabled, and a normal turn–on current ramp ensues. Again, during the load charging, the OC signal causes charging of the FLTTIME capacitor until the next delay period elapses. The sequential charging and discharging of the FLTTIME capacitor results in a typical 1% retry duty cycle. If the fault subsides, the timing capacitor is rapidly discharged, duty–cycle operation stops, and the /PG output is asserted.

Note that because of the timing inhibit during the initial slow ramp period, the duty cycle in practice is whtly greater than the nominal 1% value. However, sound current during this period peaks at only about with a maximum limit. The duty cycle of the nonal randound constant-current periods is approximately the constant of the con

The FAULT LOGIC within TIM P JCK automatically manages capacite char and discharge actions, and the enabling of the G. Jutpu

#### Supply Transient Respr 3e

The TPS2398 and Tr 32° also eature a fast-acting overload comparate which its 'clamp large (ransents from catastrophi laults turn) once the pass FE1 is fully enhanced, such a short courts. This function provide; a back-up protect to the LCA by providing a !!27d gate discharge action where LCA is saturated. If sense voltage excursions above 100 mV are detected, this comparation rapidly pulls down the GATE output, bypassing the fault timer, and terminating the short-circuit condition. Once the spike has been brought down below the over ad threshold, the GATE output is released, allowing the circuit to turn on again in either current-ramp or current-limit mode. A 4 µs deglitch filter is applied to the OL signal to help reduce the occurrence of nuisance trips.

In redundant–supply systems, the sudden switchover to a supply of higher voltage potential is one more source of large current spikes. Due to the low impedance of filter capacitance under such high–frequency transients, these spikes are generally indistinguishable from true short–circuit faults to a hot swap controller. However, the TPS2398 and TPS2399 transient response addresses this issue by providing rapid circuit–breaker protection for load faults along with minimal interruption of power flow during supply switching events. The scope plots in Figure 26 illustrate how.

Figure 26 is a scope capture of the TPS2398/99 response in a diode-OR configuration to such an input transient event. (All waveforms are referenced to the -VIN pin.) In this example, the module is initially operating from a nominal -43 V supply (relative to the backplane supply return node). At the first major time division, another power supply, with an output of -48 V, is suddenly hot swapped into a secondary, or INB, input. This sudden voltage step is reflected in the -48V\_RTN trace. On this board, the 5 V potential difference caused an 8 A spike, as shown by the I<sub>IN</sub> trace (I<sub>IN</sub> trace has been measured after the diode-OR). The GATE pin is rapidly pulled low, which quickly terminates the overload spile. However, it is quickly released, and seen to drive back the pass FET ON-threshold, in this case, about 5 V he sultant current-limit operation of the circuit ed bree 2 A load on the B supply. Once supr current. wing again, the filter capacitance is cl. .gec. \to the new input supply level, seen here on the 7DRAIN ti Once the capacitance is fully charged, the lo demand rolls off to the operating 1 A level. As an added nefit his event is transparent to the /PG signal, which m is asserted the rughout the disturbance.

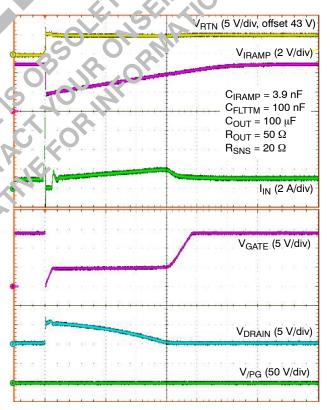


Figure 26. Input Transient Response

In order for downstream loads (bricks, etc.) to operate through the distribution bus transient, it is important to properly size the filtering capacitance to supply the needed energy during the OFF-time of the pass FET. In this example, once the RTN node jumps by 5 V higher than the original potential, about 6 V develops across the FET,

indicating approximately a 1 V droop across the brick input. Therefore, due to the fast response of the TPS2398/99 devices, the 100  $\mu F$  capacitor achieves excellent hold–up of the brick input voltage. Actual requirements depend heavily on the individual application. Whether the device turns back on in either current–ramp or current–limit mode depends in part on the size of the ramp capacitor ( $C_{IRAMP}$ ) and the input capacitance of the pass FET. But in any case, the circuit turns back on in a controlled–current manner after rapidly clamping the potentially damaging spike.

### **Setting the Sense Resistor Value**

Due to the current–limiting action of the internal LCA, the maximum allowable load current for an implementation is easily programmed by selecting the appropriate sense resistor value. The LCA acts to limit the sense voltage  $V_{\rm ISENS}$  to its internal reference. Once the voltage at the IRAMP pin exceeds approximately 4 V, this limit is the clamp voltage,  $V_{\rm REF\_K}$ . Therefore, a maximum sense resistor value can be determined from Equation 1.

$$R_{SNS(MAX)} \le \frac{V_{REF\_K(MIN)}}{I_{MAX}}$$
 (eq. 1)  
 $R_{SNS(MAX)} \le \frac{33 \text{ mV}}{I_{MAX}}$ 

#### Where:

- R<sub>SNS</sub> is the sense resistor value,
- $V_{REF\ K(MIN)}$  is the minimum re samp vo. ...d
- I<sub>MAX</sub> is the desired current lim

value it important to When setting the sense re consider two factors, the min current that may be imposed by the TPS239. PS2. ), and the maximum load under normal ratio of module. For the first factor, the spec' cation 'nin. A clamp value is used, as seen in Equatio 1. This is thou accounts for the tole arce in the sourced cu. nt lim below the typical level expected (40 mV / R<sub>SNS</sub>). (1... Lamp measurement includes LCA input offset voltage; therefore, this offset does not have to be factored into the current limit again.) Second, if the load current varies over a range of values under norther operating conditions, then the maximum load level must be allowed for by the value of R<sub>SNS</sub>. One example of this is when the load is a switching converter, or brick, which draws higher input current, for a given power output, when the distribution bus is at the low end of its operating range, with decreasing draw at higher supply voltages. To avoid current-limit operation under normal loading, some margin should be designed in between this maximum anticipated load and the minimum current limit level, or  $I_{MAX} > I_{LOAD(MAX)}$ , for Equation 1.

For example, using a 20 m $\Omega$  sense resistor for a nominal 1 A load application provides a minimum of 650 mA of overhead for load variance/margin. Typical bulk capacitor charging current during turn-on is 2 A (40 mV / 20 m $\Omega$ ).

#### Setting the Inrush Slew Rate

The TPS2398 and TPS2399 devices enable user–programming of the maximum current slew rate during load start–up events. A capacitor tied to the IRAMP pin ( $C_2$  in the typical application diagram) controls the di/dt rate. Once the sense resistor value has been established, a value for ramp capacitor  $C_{IRAMP}$  in microfarads, can be determined from Equation 2.

$$C_{IRAMP} = \frac{11}{100 \cdot R_{SNS} \cdot \left(\frac{di}{dt}\right)_{MAX}}$$
 (eq. 2)

Where:

- R<sub>SENSE</sub> is jr nms, and
- $\left(\frac{di}{dt}\right)_{X}$  is t' desired maximum slew rate, in peres cond.

For a pple, it is desired slew rate for the typical pplication hown is 1500 mA/ms, the calculated value for C<sub>IP AMP</sub> is a cut 3.7 nF. Selecting the next larger standard value of 3.9 nF (as shown in the diagram) provides some narginal capacitor and sense resistor calculated.

described earlier in this section, the TPS2398 and TFS2399 initiate remain capacitor charging, and consequently. Used current didth at a reduced rate. This reduced rate applies until the voltage on the IRAMP pin is about 5 %. The maxim on ai/dt rate, as set by Equation 2, is an edited the device has switched to the 10 μA charging so once.

## Setting the Foult Timing Capacitor

The fau't inteout period is established by the value of the capacity connected to the FLTTIME pin, C<sub>FLTTM</sub>. The timeout period permits riding out spurious current glitches and surges that may occur during operation of the system, and prevents indefinite sourcing into faulted loads swapped into a live system. However, to ensure smooth voltage ramping under all conditions of load capacitance and input supply potential, the minimum timeout should be set to accommodate these system variables. To do this, a rough estimate of the maximum voltage ramp time for a completely discharged plug—in card provides a good basis for setting the minimum timer delay.

Due to the three-phase nature of the load current at turn-on, the load voltage ramp potentially has three distinct phases (compare Figures 3 and 4). This profile depends on the relative values of load capacitance, input dc potential, maximum current limit and other factors. The first two phases are characterized by the two different slopes of the current ramp; the third phase, if required for bulk capacitance charging, is the constant-current charging at I<sub>MAX</sub>. Considering the two current ramp phases to be one period at an average di/dt simplifies calculation of the required timing capacitor.

For the TPS2398 and TPS2399, the typical duration of the soft-start ramp period, t<sub>SS</sub>, is given by Equation 3.

$$t_{SS} = 1183 \cdot C_{IRAMP}$$
 (eq. 3)

Where:

- t<sub>SS</sub> is the soft-start period in ms, and
- C<sub>IRAMP</sub> is given in μF

During this current ramp period, the load voltage magnitude which is attained is estimated by Equation 4.

$$V_{LSS} = \frac{i_{AVG}}{2 \cdot C_{LOAD} \cdot C_{RAMP} \cdot 100 \cdot R_{SNS}} \cdot t_{SS}^{2} \quad \text{(eq. 4)}$$

Where:

- V<sub>LSS</sub> is the load voltage reached during soft-start,
- i<sub>AVG</sub> is 3.38 μA for the TPS2398 and TPS2399,
- C<sub>LOAD</sub> is the amount of the load capacitance, and
- t<sub>SS</sub> is the soft-start period, in seconds

The quantity i<sub>AVG</sub> in Equation 4 is a weighted average of the two charge currents applied to C<sub>IRAMP</sub> during turn-on, considering the typical output values.

If the result of Equation 4 is larger than the maximum input supply value, then the load can be expected to rge completely during the inrush slewing portion of the inserevent. However, if this voltage is less than he mid mun supply input, V<sub>IN(MAX)</sub>, the HSPM tra itions to the constant-current charging of the load. amount of time required at I<sub>M</sub> is deter-Equation 5.

$$t_{CC} = \frac{C_{LOAD}}{V_F} \frac{(AX) - V}{AX}$$
 (eq. 5)

Where:

- t<sub>CC</sub> is the column to voltage rame, in interest in the column. • V<sub>REF\_K(MIN)</sub> is the minimum clamp voltage 33 m<sup>V</sup>/

With this information, the minimum recommended value timing capacitor C<sub>FLTTM</sub> can be determined. The delay time needed will be either a time t<sub>SS2</sub> or the sum of t<sub>SS2</sub> and t<sub>CC</sub>, according to the estimated time to charge the load. The quantity t<sub>SS2</sub> is the duration of the normal rate current ramp period, and is given by Equation 6.

$$t_{SS2} = 0.35 \cdot C_{RAMP}$$
 (eq. 6)

Where:

• C<sub>RAMP</sub> is given in microfarads

Since fault timing is generated by the constant-current charging of C<sub>FLTTM</sub>, the capacitor value is determined from either Equation or 8, as appropriate.

$$FLTTMMIN) = \frac{55 \cdot t_{SS2}}{3.75}$$
 (eq. 7)

$$C_{FLT1M(MIN)} = \frac{55 \cdot (t_{SS2} + t_{CC})}{3.75}$$
 (eq. 8)

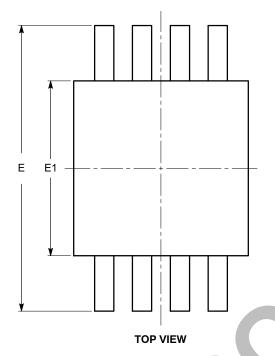
Where:

- C<sub>FLT</sub>M(MIN) is the recommended capacitor value, in m; Jfarads,
- 352 is the result of Equation 6, in seconds, and t<sub>CC</sub> is the result of Equation 5, in seconds.

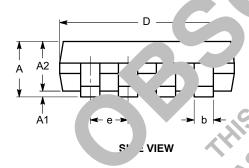
Continuing the tyrical application example, using a 100 μF input Operator (CLOAD). Equations 3 and 4 estimate the load voltage ramping to approximately -46 V during the soft-start period. If the module should operate down to 72 V input surely, approximately another 1.58 ms of con tant-current charging may be required. Therefore, I quations 6 and 8 are used to determine C<sub>FLTTM(MIN)</sub>, and he resu! of 43 nF suggests the 47 nF standard value.

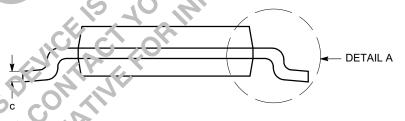
## **PACKAGE DIMENSIONS**

MSOP 8, 3x3 CASE 846AD ISSUE O

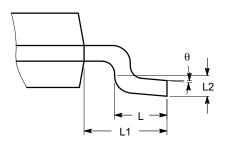


SYMBOL	MIN	NOM	MAX	
Α			1.10	
A1	0.05	0.10	0.15	
A2	0.75	0.85	0.95	
b	0.22		0.38	
С	0,13		0.23	
D	90	3.00	3.10	
-	1.81	4.90	5.00	
	2.30	3.00	3.10	
е		0.65 BSC		
Ļ	0.40	0.60	0.80	
	0.95 REF			
L2		0∙≎ BSC	0)	
θ	00	5	6°	





## **END VIEW**



DETAIL A

#### Notes:

- (1) All dimensions are in millimeters. Angles in degrees.
- (2) Complies with JEDEC MO-187.

#### **ORDERING INFORMATION**

Device	Marking	Fault Operation	Package	Shipping <sup>†</sup>
TPS2398DMT7G	2398	Latch off	MSOP-8 (Pb-Free)	3000 / Tape & Reel
TPS2399DMT7G	2399	Periodically retry	(PD-Free)	

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



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